

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: **Cann et al.**
Serial No.: **10/711,765**
Filed: **October 4, 2004**
For: **Inspection Methods and Structures for Visualizing and/or
Detecting Specific Chip Structures**
Dkt. No.: **BUR920040035US1**
Conf. No.: **5764**
Examiner: **Lee, H.**
Art Unit: **2823**

OK

to
enter

Lee

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

After-Final Amendment

Sir:

Introductory Comments

In response to the Final Office Action dated January 22, 2007, Applicants
respond as follows: